

|  |  |  |                                       |                               |
|--|--|--|---------------------------------------|-------------------------------|
| Substitute Form PTO-1449<br>(Modified)   |  | U.S. Department of Commerce<br>Patent and Trademark Office | Attorney's Docket No.<br>18239-023US1 | Application No.<br>10/597,806 |
| <b>Information Disclosure Statement<br/>by Applicant</b><br>(Use several sheets if necessary)<br>(37 CFR §1.98(b)) |  | Applicant<br>Bernhard Kneer et al.                         |                                       |                               |
|  |  | Filing Date<br>August 8, 2006                              | Group Art Unit<br>3722                |                               |

| <b>U.S. Patent Documents</b> |           |                 |                  |                               |       |          |                            |
|------------------------------|-----------|-----------------|------------------|-------------------------------|-------|----------|----------------------------|
| Examiner Initial             | Desig. ID | Document Number | Publication Date | Patentee                      | Class | Subclass | Filing Date If Appropriate |
|                              | AA        | 2005/0248856    | 11/2005          | Omura et al.                  |       |          |                            |
|                              | AB        | 2003/174408     | 9/8/2003         | Rostalski Hans-Juergen et al. |       |          |                            |
|                              | AC        | 2004/0109237    | 6/10/2004        | Epple et al.                  |       |          |                            |
|                              | AD        | 2007/0052936    | 3/8/2007         | Philips                       |       |          |                            |
|                              | AE        | 2005/024609     | 2/3/2005         | De Smit et al.                |       |          |                            |
|                              | AF        | 2005/0219707    | 10/6/2005        | Schuster et al.               |       |          |                            |
|                              | AG        | 2005/0225737    | 10/13/2005       | Weissenreider et al.          |       |          |                            |
|                              | AH        | 2006/0221582    | 10/5/2006        | DeNies et al.                 |       |          |                            |
|                              | AI        | 2005/0190455    | 9/1/2005         | Rostalski et al.              |       |          |                            |
|                              | AJ        | 2005/0179877    | 8/18/2005        | Mulkens et al.                |       |          |                            |
|                              | AK        | 2003/0174408    | 9/18/2003        | Rostalski et al.              |       |          |                            |
|                              | AL        | 2005/0161644    | 7/28/2005        | Zhang et al.                  |       |          |                            |
|                              | AM        | 2005/0117224    | 6/2/2005         | Shafer et al.                 |       |          |                            |
|                              | AN        | 2005/074704     | 4/7/2005         | Endo et al.                   |       |          |                            |
|                              | AO        | 2005/0068499    | 3/31/2005        | Docdoc et al.                 |       |          |                            |
|                              | AP        | 2005/0024609    | 2/3/2005         | De Smit et al.                |       |          |                            |
|                              | AQ        | 4,346,164       | 8/24/1982        | Tabarelli et al.              |       |          |                            |
|                              | AR        | 4,890,903       | 1/2/1990         | Treisman et al.               |       |          |                            |
|                              | AS        | 5,682,263       | 10/1997          | Robb et al.                   |       |          |                            |
|                              | AT        | 6,181,485       | 1/2001           | He, Chuan                     |       |          |                            |
|                              | AU        | 2005/0074704    | 4/7/2005         | Endo et al.                   |       |          |                            |
|                              | AV        | 2006/0187430    | 8/24/2006        | Docdoc et al.                 |       |          |                            |
|                              | AW        | 2005/074704     | 4/7/2005         | Endo et al.                   |       |          |                            |
|                              | AX        | 2005/0179877    | 8/18/2005        | Mulkens et al.                |       |          |                            |
|                              | AY        | 2005/0219707    | 10/6/2005        | Schuster et al.               |       |          |                            |
|                              | AZ        | 6,809,794       | 10/26/2004       | Sewell                        |       |          |                            |
|                              | AAA       | 2004/075895     | 04/22/2004       | Jeng et al.                   |       |          |                            |

|                    |                 |
|--------------------|-----------------|
| Examiner Signature | Date Considered |
|--------------------|-----------------|

EXAMINER: Initials citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

|  |  |  |                                       |                               |
|--|--|--|---------------------------------------|-------------------------------|
| Substitute Form PTO-1449<br>(Modified)   |  | U.S. Department of Commerce<br>Patent and Trademark Office | Attorney's Docket No.<br>18239-023US1 | Application No.<br>10/597,806 |
| <b>Information Disclosure Statement<br/>by Applicant</b><br>(Use several sheets if necessary)<br><br>(37 CFR §1.98(b)) |  | Applicant<br>Bernhard Kneer et al.                         |                                       |                               |
|  |  | Filing Date<br>August 8, 2006                              | Group Art Unit<br>3722                |                               |

| <b>U.S. Patent Documents</b> |           |                 |                  |                      |       |          |                            |
|------------------------------|-----------|-----------------|------------------|----------------------|-------|----------|----------------------------|
| Examiner Initial             | Desig. ID | Document Number | Publication Date | Patentee             | Class | Subclass | Filing Date If Appropriate |
|                              | ABB       | 5,900,354       | 05/04/1999       | Batchelder et al.    |       |          |                            |
|                              | ACC       | 7,187,503       | 03/06/2007       | Rostalski et al.     |       |          |                            |
|                              | ADD       | 2006/0012885    | 01/19/2006       | Beder et al.         |       |          |                            |
|                              | AEE       | 2007/0091451    | 04/26/2007       | Schuster             |       |          |                            |
|                              | AFF       | 2007/0109659    | 05/17/2007       | Rostalski et al.     |       |          |                            |
|                              | AGG       | 2006/0221456    | 10/05/2006       | Shafer et al.        |       |          |                            |
|                              | AHH       | 2005/0225737    | 10/13/2005       | Weissenrieder et al. |       |          |                            |
|                              | AII       | 2006/0244938    | 11/02/2006       | Schuster             |       |          |                            |
|                              | AJJ       | 2006/0066962    | 03/30/06         | Totzeck et al.       |       |          |                            |
|                              | AKK       | 2005/0190435    | 09/01/2005       | Shafer et al.        |       |          |                            |

| <b>Foreign Patent Documents or Published Foreign Patent Applications</b> |           |                 |                  |                          |             |          |
|--|-----------|-----------------|------------------|--------------------------|-------------|----------|
| Examiner Initial   | Desig. ID | Document Number | Publication Date | Country or Patent Office | Class       | Subclass |
|  |           |                 |                  |                          | Translation |          |
|  |           |                 |                  |                          | Yes         | No       |
|  | ALL       | EP0291596       | 1/19/1994        | EPO                      |             |          |
|  | AMM       | WO 2005/059617  | 6/30/2005        | WIPO                     |             |          |
|  | ANN       | WO 2006/045748  | 5/4/2006         | WIPO                     |             |          |
|  | AOO       | WO 2005/006026  | 1/20/2005        | WIPO                     |             |          |
|  | APP       | WO 2005/081067  | 9/1/2005         | WIPO                     |             |          |
|  | AQQ       | WO 2005/059645  | 6/30/2005        | WIPO                     |             |          |
|  | ARR       | WO 2005/059618  | 6/30/2005        | WIPO                     |             |          |
|  | ASS       | WO 2004/019128  | 3/4/2004         | WIPO                     |             |          |
|  | ATT       | WO 2005/031823  | 4/7/2005         | WIPO                     |             |          |
|  | AUU       | EP 1522894      | 4/13/2005        | EPO                      |             |          |
|  | AVV       | EP 1486827      | 12/15/2004       | EPO                      |             |          |
|  | AWW       | EP 0023231      | 2/4/1981         | EPO                      |             |          |
|  | AXX       | DD 221563       | 4/24/1985        | Germany                  |             |          |
|  | AYY       | DD 224448       | 7/3/1985         | Germany                  |             |          |

|  |                 |
|--|-----------------|
| Examiner Signature   | Date Considered |
| EXAMINER: Initials citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant. |                 |

|  |  |  |                                       |                               |
|--|--|--|---------------------------------------|-------------------------------|
| Substitute Form PTO-1449<br>(Modified)   |  | U.S. Department of Commerce<br>Patent and Trademark Office | Attorney's Docket No.<br>18239-023US1 | Application No.<br>10/597,806 |
| <b>Information Disclosure Statement<br/>by Applicant</b><br>(Use several sheets if necessary)<br><br>(37 CFR §1.98(b)) |  | Applicant<br>Bernhard Kneer et al.                         |                                       |                               |
|  |  | Filing Date<br>August 8, 2006                              | Group Art Unit<br>3722                |                               |

### Foreign Patent Documents or Published Foreign Patent Applications

| Examiner Initial | Desig. ID | Document Number | Publication Date | Country or Patent Office | Class | Subclass | Translation |    |
|------------------|-----------|-----------------|------------------|--------------------------|-------|----------|-------------|----|
|                  |           |                 |                  |                          |       |          | Yes         | No |
|                  | AZZ       | EP 1420302      | 5/19/2004        | EPO                      |       |          |             |    |
|                  | AAAA      | EP 1524558      | 4/20/2005        | EPO                      |       |          |             |    |
|                  | ABBB      | JP 07220990     | 8/18/1995        | Japan                    |       |          |             |    |
|                  | ACCC      | JP10-228661     | 8/25/1998        | Japan                    |       |          |             |    |
|                  | ADDD      | JP10-303114     | 11/13/1998       | Japan                    |       |          |             |    |
|                  | AEEE      | EP 1 645 911    | 04/12/2006       | EPO                      |       |          |             |    |
|                  | AFFF      | EP 1 557 721    | 07/25/2005       | EPO                      |       |          |             |    |
|                  | AGGG      | EP 1 489 462    | 12/22/2004       | EPO                      |       |          |             |    |
|                  | AHHH      | EP 1 630 616    | 03/01/2006       | EPO                      |       |          |             |    |

### Other Documents (include Author, Title, Date, and Place of Publication)

| Examiner Initial | Desig. ID | Document  |
|------------------|-----------|---|
|                  | AIII      | Burnett et al., "High Index Materials for 193 nm immersion Lithography", International Symposium on Immersion & 157 nm Lithography, February 8, 2004, pp 3, figure 1.   |
|                  | AJJJ      | Dammel et al., "193 nm Immersion Lithography – Taking the Plunge", Journal of Photopolymer Science and Technology, vol. 17 no. 4, pp 587-607 (2004).  |
|                  | AKKK      | Kawata et al., "Fabrication of 0.2mm Fine Patterns Using Optical Projection Lithography With an Oil Immersion Lens", Japanese Journal of Applied Physics, Japan Society of Applied Physics, Tokyo, Japan, vol. 31 no. 12B, Part 1, December 1, 1992, pp 4174-4177.  |
|                  | ALLL      | Owa et al., "Immersion Lithography; its Potential Performance Issues", Proceeding of the SPIE, SPIE, Bellingham, VA, vol. 5040 no. 1, February 28, 2003, pp 724-733.  |
|                  | AMMM      | J.A. Hoffnagle et al., "Liquid Immersion Deep-Ultraviolet Interferometric Lithography", Journal of Vacuum Science & Technology B:Microelectronics Processing and Phenomena, American Vacuum Society, New York, NY, Vol. 17, No. 6, November 1999 (199-11) pp 3306-3309.   |
|                  | ANNN      | Smith, Bruce, "Water-based 193nm Immersion Lithography", Online!, <a href="http://www.sematech.org/resources/litho/meetings/immersion/20040128/presentations/06%20rit20\$microstepper%20effortsSmith.pdf">http://www.sematech.org/resources/litho/meetings/immersion/20040128/presentations/06%20rit20\$microstepper%20effortsSmith.pdf</a> , (January 28, 2004). |

|  |                 |
|--|-----------------|
| Examiner Signature   | Date Considered |
| EXAMINER: Initials citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant. |                 |